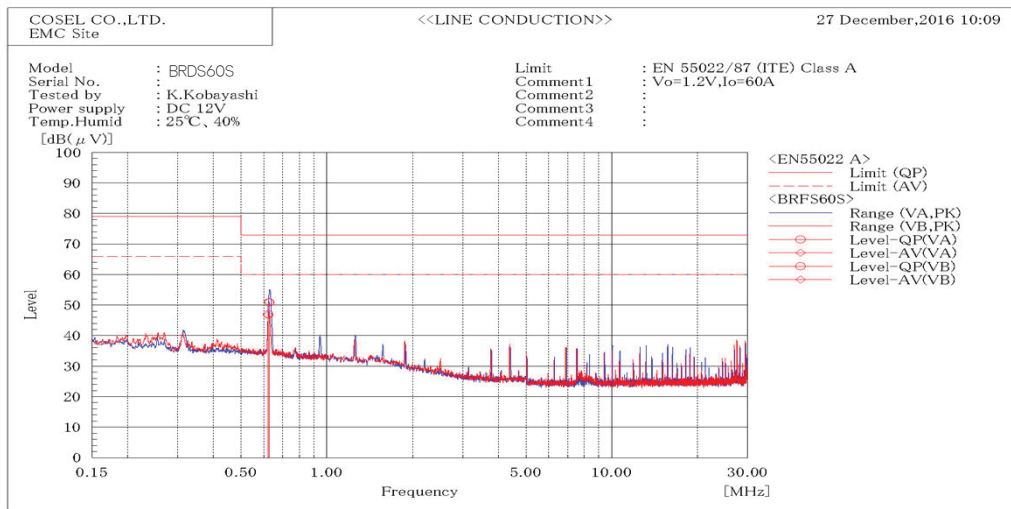
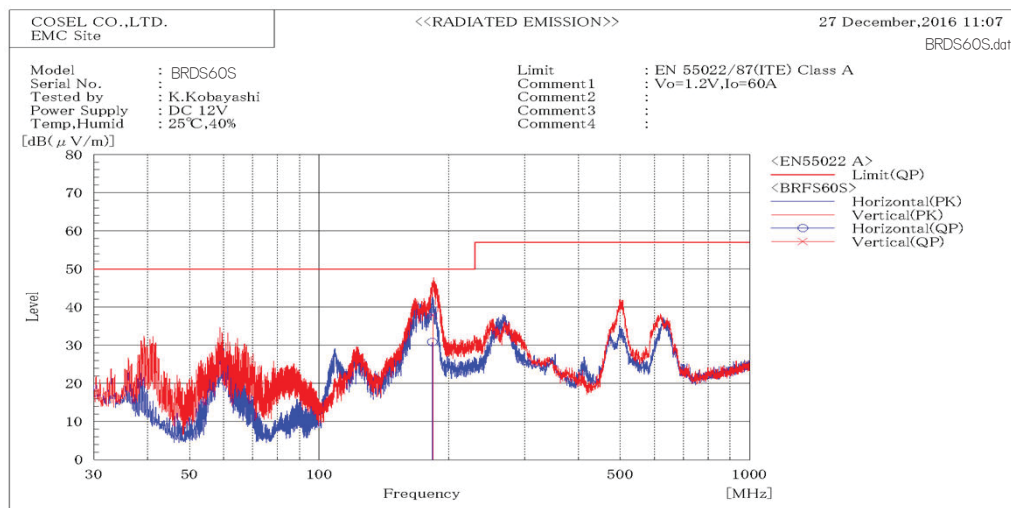


DATA SHEET		Date	29-Dec-16
Model	BRDS60S	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi



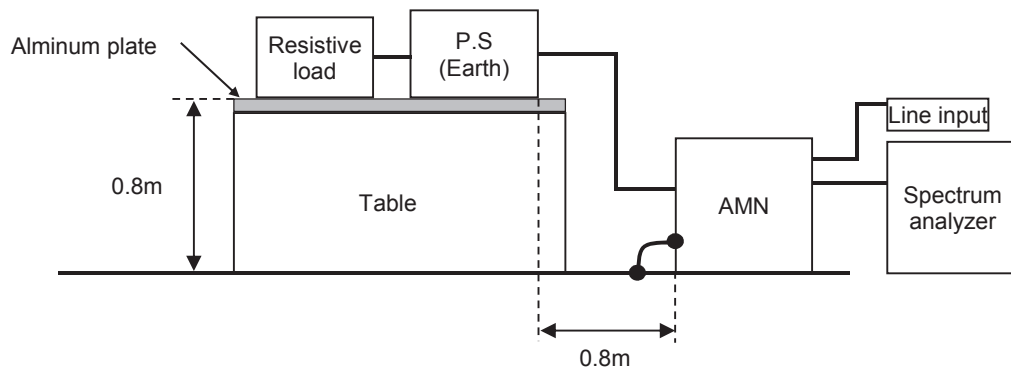
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.62219	VB	46.9	46.8	73	60	26.1	13.2	Pass	
0.62671	VA	50.9	51.1	73	60	22.1	8.9	Pass	



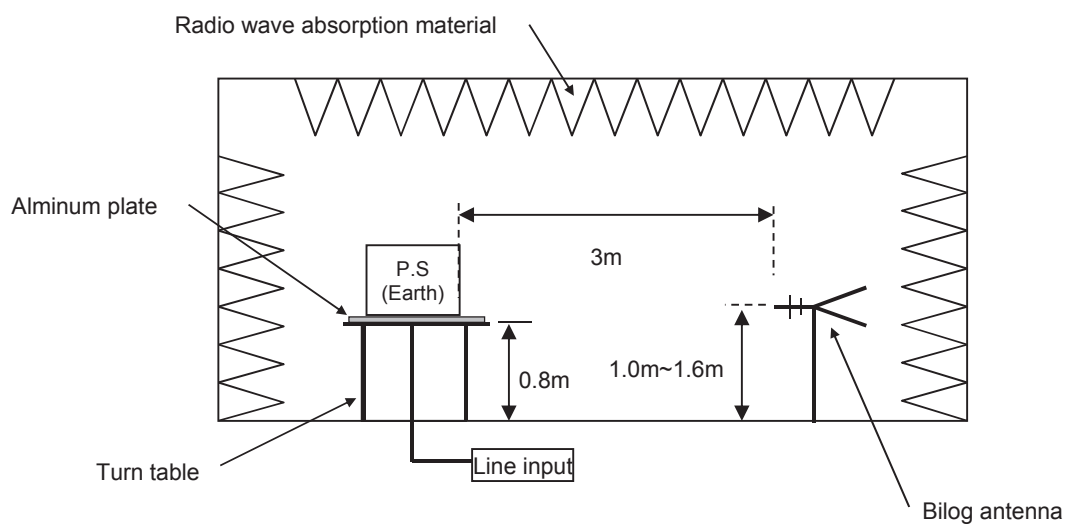
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
183.013	H	Stable	30.9	50.0	19.1	Pass	114	89	
183.533	V	Stable	38.0	50.0	12.0	Pass	109	15	

DATA SHEET		Date	29-Dec-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi

1. Line conduction



2. Radiated emission

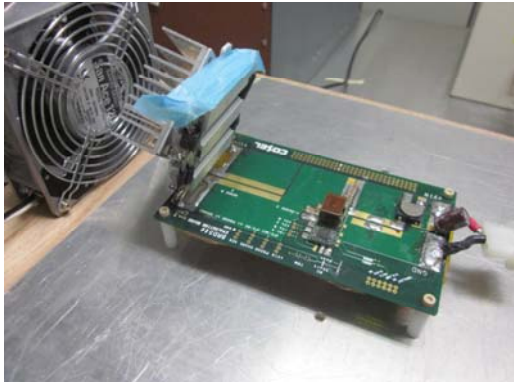


Conditions

Test : EMI
Model Name : BRDS60S

○Photographs of Test Set-Up

LINE CONDUCTION

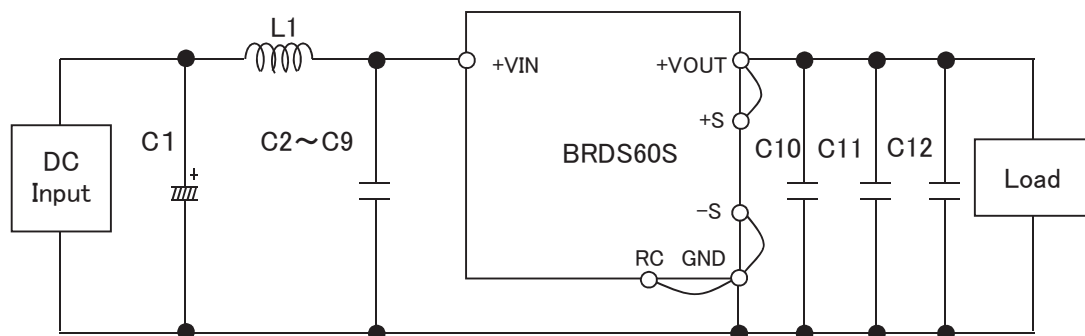


RADIATED EMISSION



○Testing circuitry

○Test Circuit



C1	: 25V	470 μ F	Electrolytic capacitor
C2~C9	: 16V	22 μ F	Ceramic capacitor
C10~C12	: 6.3V	100 μ F	Ceramic capacitor
L1	: 0.3 μ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)